

CALL FOR PAPERS

Special Section on Recent Developments on Reliability, Maintainability and Dependability

The IEICE Transactions on Fundamentals of Electronics, Communications and Computer Sciences announces a forthcoming Special Section on Recent Developments on Reliability, Maintainability and Dependability to be published in **October, 2015**.

The objective of the Special Section is to discuss new theoretical and practical development in reliability, maintainability and dependability, especially focused on mathematical modeling. The special section solicits paper submission particularly from, but not restricted to, researchers who presented their original works in the 6th Asia-Pacific International Symposium on Advanced Reliability and Maintenance Modeling (APARM 2014).

Topics of interest include, but are not limited to:

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|--------------------------------------|---------------------------------|--------------------------|
| Accelerated Life Testing | Bayesian Reliability | Communication Systems |
| Computer System Reliability | Dependability Modeling | Design for Six Sigma |
| Estimation and Statistical Tests | Fault-tolerant Computing | Human Reliability |
| Internet Reliability Engineering | Maintenance Modeling | Maintenance Optimization |
| Network Reliability and Optimization | Safety and Risk Assessment | Security Issues |
| Software Reliability and Testing | Service and Reliability | System Reliability |
| Survival Analysis | Warranty Analysis Manufacturing | |

Submission Guidelines:

Submit a paper and transfer copyright of the paper using the IEICE Web site https://review.ieice.org/regist/regist_baseinfo_e.aspx by **November 30, 2014**. Authors should choose the “[Special-RM] Recent Developments on Reliability, Maintainability and Dependability” as a “Journal/Section” on the online screen. Do not choose [Regular-EA]. We accept papers only in PDF format. Inquiries to

Tetsushi Yuge

Associate Professor, Dept. Electrical and Electronic Eng., National Defense Academy

1-10-20 Hashirimizu, Yokosuka, Kanagawa, 239-8686 Japan

E-mail: yuge@nda.ac.jp Phone: +81.46.841.3810 FAX: +81.46.844.5903

Manuscripts should be prepared according to the style guidelines for the IEICE Transactions (See http://www.ieice.org/eng/shiori/mokuji_ess.html). In this special section, the length of the manuscript should be no longer than eight printed pages for a PAPER and two printed pages for a LETTER. Submissions that do not follow the above instructions will not be accepted. The term for revision after the review process might be shortened, although it is usually 60 days' long. Some papers may appear in the following transactions, if the number of accepted papers exceeds the limit. At least one of the authors must be an IEICE member when the manuscript is submitted for review. Please note that if accepted, authors are requested to pay for the page charges covering partial costs of publications.

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